INTEGRATED CIRCUITS

DATA SHEET

74ABT657

Octal transceiver with parity generator/checker (3-State)

Product specification

1995 Dec 11

IC23 Data Handbook





Octal transceiver with parity generator/checker (3-State)

74ABT657

FEATURES

- Combinational functions in one package
- Low static and dynamic power dissipation with high speed and high output drive
- Output capability: +64mA/-32mA
- Power-up 3-State
- Latch-up protection exceeds 500mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model

DESCRIPTION

The 74ABT657 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT657 is an octal transceiver featuring non-inverting buffers with 3-State outputs and an 8-bit parity generator/checker, and is intended for bus-oriented applications. The buffers have a guaranteed current sinking capability of 64mA. The Transmit/Receive (T/R) input determines the direction of the data flow through the bidirectional transceivers. Transmit (active-High) enables data from A ports to B ports; Receive (active-Low) enables data from B ports to A ports.

The Output Enable (OE) input disables both the A and B ports by placing them in a high impedance condition when the OE input is High. The parity select (ODD/EVEN) input gives the user the option of odd or even parity systems. The parity (PARITY) pin is an output from the generator/checker when transmitting from the port A to B $(T/\overline{R} = High)$ and an input when receiving from port B to A port $(T/\overline{R} = High)$ = Low). When transmitting $(T/\overline{R} = High)$ the parity select (ODD/EVEN) input is set, then the A port data is polled to determine the number of High bits. The parity (PARITY) output then goes to the logic state determined by the parity select (ODD/EVEN) setting and by the number of High bits on port A. For example, if the parity select (ODD/EVEN) is set Low (even parity), and the number of High bits on port A is odd, then the parity (PARITY) output will be High, transmitting even parity. If the number of High bits on port A is even, then the parity (PARITY) output will be Low, keeping even parity. When in receive mode $(T/\overline{R} = Low)$ the B port is polled to determine the number of High bits. If parity select (ODD/EVEN) is Low (even parity) and the number of Highs on port B is:

- odd and the parity (PARITY) input is High, then ERROR will be High, signifying no error.
- (2) even and the parity (PARITY) input is High, then ERROR will be asserted Low, indicating an error.

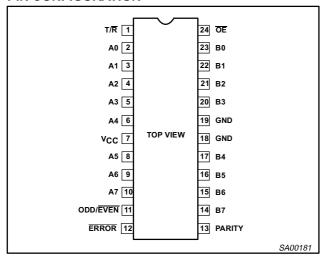
QUICK REFERENCE DATA

| SYMBOL | PARAMETER | CONDITIONS T _{amb} = 25°C; GND = 0V | TYPICAL | UNIT |
|--------------------------------------|---|---|---------|------|
| t _{PLH} t _{PHL} | Propagation delay An to Bn or Bn to An | $C_L = 50pF; V_{CC} = 5V$ | 3.3 | ns |
| C _{IN} | Input capacitance | V _I = 0V or V _{CC} | 4 | pF |
| C _{I/O} | I/O capacitance | Outputs disabled; V _O = 0V or V _{CC} | 7 | pF |
| I _{CCZ} | Total supply current | Outputs disabled; V _{CC} =5.5V | 500 | nA |

ORDERING INFORMATION

| PACKAGES | TEMPERATURE RANGE | OUTSIDE NORTH AMERICA | NORTH AMERICA | DWG NUMBER |
|-----------------------------|-------------------|-----------------------|---------------|------------|
| 24-Pin Plastic DIP | –40°C to +85°C | 74ABT657 N | 74ABT657 N | SOT222-1 |
| 24-Pin plastic SO | -40°C to +85°C | 74ABT657 D | 74ABT657 D | SOT137-1 |
| 24-Pin Plastic SSOP Type II | -40°C to +85°C | 74ABT657 DB | 74ABT657 DB | SOT340-1 |
| 24-Pin Plastic TSSOP Type I | –40°C to +85°C | 74ABT657 PW | 74ABT657PW DH | SOT355-1 |

PIN CONFIGURATION



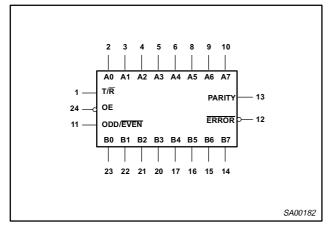
PIN DESCRIPTION

| SYMBOL | PIN NUMBER | NAME AND FUNCTION |
|-----------------------------------|----------------------|----------------------------------|
| 13 | PARITY | Parity output |
| 11 | ODD/ EVEN | Parity select input |
| 12 | ERROR | Error output |
| 1 | T/R | Transmit/receive input |
| 2, 3, 4, 5, 6, 8, 9, 10 | A0 - A7 | A port 3-State outputs |
| 23, 22, 21, 20, 17, 16, 15, 14 | B0 - B7 | B port 3-State outputs |
| 24 | ŌĒ | Output enable input (active-Low) |
| 18, 19 | GND | Ground (0V) |
| 7 | V _{CC} | Positive supply voltage |

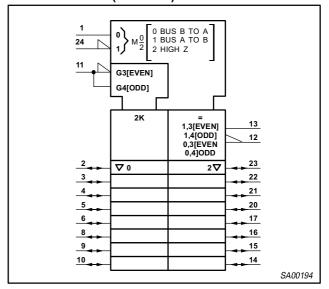
Octal transceiver with parity generator/checker (3-State)

74ABT657

LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



FUNCTION TABLE

| NUMBER OF HIGH INPUTS | INPUTS | | | INPUT/ OUTPUT | OUTPUTS | |
|-----------------------|------------------|-------------------|------------------|----------------------------|-----------------------|--|
| | ŌĒ | T/R | ODD/EVEN | PARITY | ERROR | OUTPUTS MODE |
| 0, 2, 4, 6, 8 | L L L L | H L L L | H H H L | H L H L | Z Z H L L | Transmit Transmit Receive Receive Receive Receive |
| 1, 3, 5, 7 | L L L | H H L L L L | H | L H H L H L | Z Z L H L | Transmit Transmit Receive Receive Receive Receive |
| Don't care | Н | Х | Х | Z | Z | 3-State |

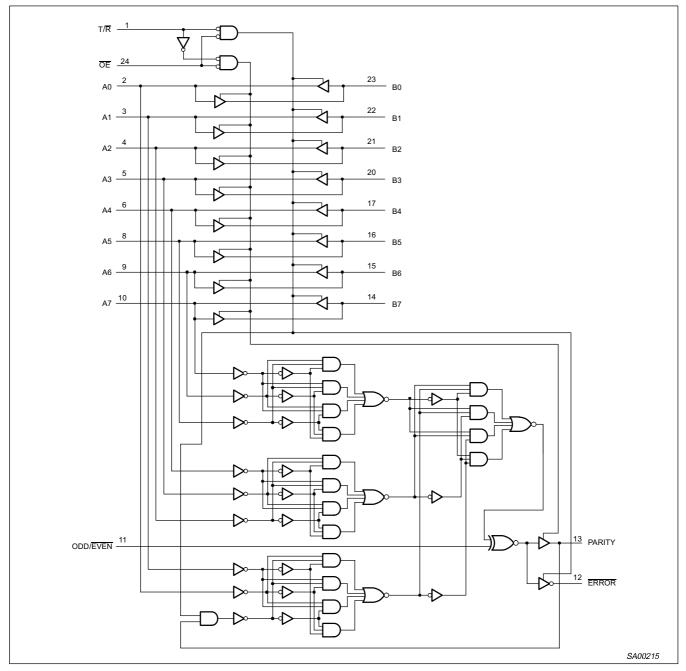
H = High voltage level
L = Low voltage level
X = Don't care
Z = High impedance "o

High impedance "off" state

Octal transceiver with parity generator/checker (3-State)

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LOGIC DIAGRAM



Octal transceiver with parity generator/checker (3-State)

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ABSOLUTE MAXIMUM RATINGS^{1, 2}

| SYMBOL | PARAMETER | CONDITIONS | RATING | UNIT |
|------------------|--------------------------------|-----------------------------|--------------|------|
| V _{CC} | DC supply voltage | | -0.5 to +7.0 | V |
| I _{IK} | DC input diode current | V ₁ < 0 | -18 | mA |
| VI | DC input voltage ³ | | -1.2 to +7.0 | V |
| l _{ok} | DC output diode current | V _O < 0 | -50 | mA |
| V _{OUT} | DC output voltage ³ | output in Off or High state | -0.5 to +5.5 | V |
| l _{OUT} | DC output current | output in Low state | 128 | mA |
| T _{stg} | Storage temperature range | | -65 to 150 | °C |

NOTES:

- Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
 The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
 The input and output voltage ratings may be exceeded if the input and output retries are observed.
- 3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

| SYMBOL | PARAMETER | LIM | UNIT | |
|------------------|--------------------------------------|------------|-----------------|------|
| OTMBOL | TANAMETER | Min | Max | ONT |
| Vcc | DC supply voltage | 4.5 | 5.5 | V |
| VI | Input voltage | 0 | V _{CC} | V |
| V_{IH} | High-level input voltage | 2.0 | | V |
| V _{IL} | Low-level input voltage | | 0.8 | V |
| I _{OH} | High-level output current | | -32 | mA |
| I _{OL} | Low-level output current | | 64 | mA |
| Δt/Δν | Input transition rise or fall rate | 0 | 5 | ns/V |
| T _{amb} | Operating free-air temperature range | –40 | +85 | °C |

Octal transceiver with parity generator/checker (3-State)

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DC ELECTRICAL CHARACTERISTICS

| | | | | | | LIMITS | | | |
|---|---|----------------|---|-----|--------------------------|--------|-----|-----------------|------|
| SYMBOL VIK VOH VOL II IOFF IPUIPD IIH + IOZH IIL + IOZL ICEX IO ICCH | PARAMETER | | TEST CONDITIONS | | T _{amb} = +25°C | | | : –40°C 85°C | UNIT |
| | | | | Min | Тур | Max | Min | Max | |
| V_{IK} | Input clamp volt | age | $V_{CC} = 4.5V; I_{IK} = -18mA$ | | -0.9 | -1.2 | | -1.2 | V |
| | | | V_{CC} = 4.5V; I_{OH} = -3mA; V_I = V_{IL} or V_{IH} | 2.5 | 3.5 | | 2.5 | | V |
| V_{OH} | High-level outpu | ıt voltage | V_{CC} = 5.0V; I_{OH} = -3mA; V_I = V_{IL} or V_{IH} | 3.0 | 4.0 | | 3.0 | | V |
| | | | $V_{CC} = 4.5V$; $I_{OH} = -32mA$; $V_{I} = V_{IL}$ or V_{IH} | 2.0 | 2.6 | | 2.0 | | V |
| V_{OL} | Low-level output voltage | | V_{CC} = 4.5V; I_{OL} = 64mA; V_I = V_{IL} or V_{IH} | | 0.42 | 0.55 | | 0.55 | V |
| II | Input leakage | Control pins | V _{CC} = 5.5V; V _I = GND or 5.5V | | ±0.01 | ±1.0 | | ±1.0 | μΑ |
| | current | Data pins | V _{CC} = 5.5V; V _I = GND or 5.5V | | ±5 | ±100 | | ±100 | μΑ |
| I _{OFF} | Power-off leaka | ge current | V_{CC} 0.0V; V_{O} or $V_{I} \le 4.5V$ | | ±5.0 | ±100 | | ±100 | μΑ |
| I _{PU} I _{PD} | Power-up/down 3-State output current ³ | | V_{CC} 2.0V; V_O = 0.5V; V_I = GND or V_{CC} ; V_{OE} = V_{CC} | | ±5.0 | ±50 | | ±50 | μΑ |
| I _{IH} + I _{OZH} | 3-State output High current | | $V_{CC} = 5.5V; V_{O} = 2.7V; V_{I} = V_{IL} \text{ or } V_{IH}$ | | 5.0 | 50 | | 50 | μΑ |
| I _{IL} + I _{OZL} | 3-State output Low current | | $V_{CC} = 5.5V; V_{O} = 0.5V; V_{I} = V_{IL} \text{ or } V_{IH}$ | | -5.0 | -50 | | -50 | μΑ |
| I _{CEX} | Output High leakage current | | V_{CC} = 5.5V; V_{O} = 5.5V; V_{I} = GND or V_{CC} | | 5.0 | 50 | | 50 | μΑ |
| Io | Output current ¹ | | V _{CC} = 5.5V; V _O = 2.5V | -50 | -80 | -180 | -50 | -180 | mA |
| Іссн | | | V_{CC} = 5.5V; Outputs High, V_I = GND or V_{CC} | | 0.5 | 250 | | 250 | μΑ |
| I _{CCL} | Quiescent supp | ly current | V_{CC} = 5.5V; Outputs Low, V_I = GND or V_{CC} | | 20 | 30 | | 30 | mA |
| I _{CCZ} | 1 | | V_{CC} = 5.5V; Outputs 3-State; V_I = GND or V_{CC} | | 0.5 | 250 | | 250 | μА |
| | | | Outputs enabled, one data input at 3.4V, other inputs at V_{CC} or GND; V_{CC} = 5.5V | | 0.5 | 1.5 | | 1.5 | mA |
| Δl _{CC} | Additional supplinput pin ² | ly current per | Outputs 3-State, one data input at 3.4V, other inputs at V_{CC} or GND; V_{CC} = 5.5V | | 50 | 250 | | 250 | μΑ |
| | | | Outputs 3-State, one enable input at 3.4V, other inputs at V_{CC} or GND; V_{CC} = 5.5V | | 0.5 | 1.5 | | 1.5 | mA |

NOTES:

- Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
 This is the increase in supply current for each input at 3.4V.
 This parameter is valid for any V_{CC} between 0V and 2.1V with a transition time of up to 10msec. For V_{CC} = 2.1V to V_{CC} = 5V ± 10%, a transition time of up to 100µsec is permitted.

Octal transceiver with parity generator/checker (3-State)

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SA00220

AC CHARACTERISTICS

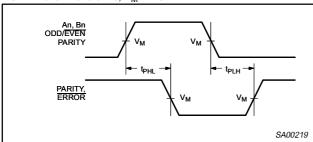
GND = 0V; t_R = t_F = 2.5ns; C_L = 50pF, R_L = 500 Ω

| | | WAVEFORMS | LIMITS | | | | | |
|--------------------------------------|--|-----------|---|------------|--------------|--|--------------|----|
| SYMBOL | PARAMETER | | T _{amb} = +25°C V _{CC} = +5.0V | | | T _{amb} = -44 V _{CC} = +5 | UNIT | |
| | | | Min | Тур | Max | Min | Max | 1 |
| t _{PLH} t _{PHL} | Propagation delay An to Bn or Bn to An | 2 | 1.1 1.2 | 3.3 3.0 | 5.0 4.3 | 1.1 1.2 | 5.5 4.8 | ns |
| t _{PLH} t _{PHL} | Propagation delay An to PARITY | 1, 2 | 2.5 2.8 | 6.5 7.0 | 8.7 9.1 | 2.5 2.8 | 10.1 10.6 | ns |
| t _{PLH} t _{PHL} | Propagation delay ODD/EVEN to PARITY, ERROR | 1, 2 | 1.7 1.9 | 5.0 5.0 | 6.6 6.6 | 1.7 1.9 | 7.3 7.3 | ns |
| t _{PLH} t _{PHL} | Propagation delay Bn to ERROR | 1, 2 | 3.9 4.0 | 9.2 9.6 | 11.7 12.1 | 3.9 4.0 | 13.8 14.5 | ns |
| t _{PLH} t _{PHL} | Propagation delay PARITY to ERROR | 1, 2 | 2.7 3.2 | 6.0 6.4 | 7.6 8.0 | 2.7 3.2 | 9.4 9.4 | ns |
| t _{PZH} t _{PZL} | Output enable time ¹ to High or Low level | 3, 4 | 1.3 1.9 | 3.8 4.4 | 5.6 7.0 | 1.3 1.9 | 6.6 8.2 | ns |
| t _{PHZ} t _{PLZ} | Output disable time from High or Low level | 3, 4 | 2.4 2.7 | 5.1 5.4 | 7.0 7.6 | 2.4 2.7 | 7.6 8.1 | ns |

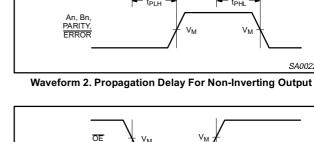
NOTES:

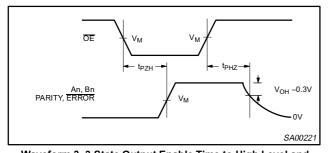
AC WAVEFORMS

NOTE: For all waveforms, $V_M = 1.5V_1$

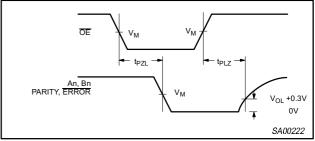


Waveform 1. Propagation Delay For Inverting Output





Waveform 3. 3-State Output Enable Time to High Level and **Output Disable Time from High Level**



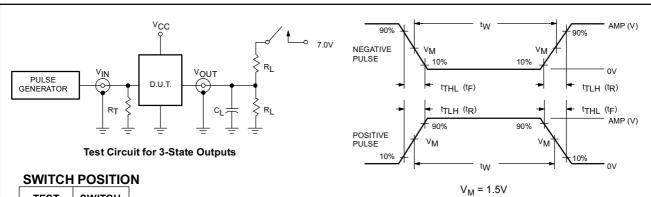
Waveform 4. 3-State Output Enable Time to Low Level and **Output Disable Time from Low Level**

These delay times reflect the 3-State recovery time only and do not include the delay through the buffers and the parity check circuitry which affect the ERROR output. To assure valid information at the ERROR pin, time must be allowed for the signal to propagate through the drivers (B to A), through the parity check circuitry (same as A to PARITY), and to the ERROR output. Valid data at the ERROR pin ≥ (B to A) + (A to PARITY).

Octal transceiver with parity generator/checker (3-State)

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TEST CIRCUIT AND WAVEFORM



| TEST | SWITCH |
|------------------|--------|
| t _{PLZ} | closed |
| t _{PZL} | closed |
| All other | open |

DEFINITIONS

R_L = Load resistor; see AC CHARACTERISTICS for value.

C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.

 R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

| FAMILY | INPUT PULSE REQUIREMENTS | | | | | | |
|--------|--------------------------|-----------|----------------|----------------|----------------|--|--|
| FAMILY | Amplitude | Rep. Rate | t _W | t _R | t _F | | |
| 74ABT | 3.0V | 1MHz | 500ns | 2.5ns | 2.5ns | | |

Input Pulse Definition

SA00012

| Octal transceiver with parity generator/checker (3-State) | 74ABT657 | |
|---|----------|--|
| DIP24: plastic dual in-line package; 24 leads (300 mil) | SOT222-1 | |
| SO24: plastic small outline package; 24 leads; body width 7.5 mm | SOT137-1 | |
| SSOP24: plastic shrink small outline package; 24 leads; body width 5.3 mm | SOT340-1 | |
| TSSOP24: plastic thin shrink small outline package; 24 leads; body width 4.4 mm | SOT355-1 | |

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NOTES

Octal transceiver with parity generator/checker (3-State)

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| | DEFINITIONS | | | | | |
|--|----------------|--|--|--|--|--|
| Data Sheet Identification | Product Status | Definition | | | | |
| Objective Specification Formative or in Design This data sheet contains the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for product development of the design target or goal specifications for the desi | | | | | | |
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